

**Search Notes**

Application/Control No.

10/532,632

Examiner

Emmanuel Bayard

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	299	1/31/2007	EB
375	267	1/31/2007	EB
375	150	1/31/2007	EB
375	349	1/31/2007	EB
375	347	1/31/2007	EB
375	295	1/31/2007	EB
370	335	1/31/2007	EB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	1/31/2007	EB